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Notice of References Cited	Application/Control No. <div style="text-align: center;">10/060,058</div>		Applicant(s)/Patent Under Reexam <div style="text-align: center;">Ueno et al.</div>	
	Examiner <div style="text-align: center;">Tu M. Nguyen</div>		Art Unit <div style="text-align: center;">3748</div>	Page 1 of 1

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		Document Number <small>Country Code-Number-Kind Code</small>	Date <small>MM-YYYY¹</small>	Name	Classification ²	
	A	5,956,947	9/1999	Tanaka et al.	60	297
	B	5,396,764	3/1995	Rao et al.	60	287
	C	5,097,665	3/1992	Kammel	60	288
	D	5,761,902	6/1998	Usami et al.	60	288
	E	5,946,906	9/1999	Akazaki et al.	60	297
	F	6,012,284	1/2000	Tanaka et al.	60	297
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NON-PATENT DOCUMENTS

		Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
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² Classifications may be U.S. or foreign.